

Notice of References Cited	Application/Control No. 10/816,915	Applicant(s)/Patent Under Reexamination TAKEUCHI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0090754	07-2002	Chan et al.	438/108
*	B	US-6,613,449	09-2003	Yamaguchi et al.	428/620
*	C	US-2004/0261904	12-2004	Chen et al.	148/023
*	D	US-6,798,072	09-2004	Kajiware et al.	257/778
*	E	US-6,617,046	09-2003	Noro et al.	428/620
*	F	US-2003/0080437	05-2003	Gonzalez et al.	257/778
*	G	US-6,193,136	02-2001	Higashi et al.	228/106
*	H	US-5,985,043	11-1999	Zhou et al.	148/24
*	I	US-6,437,450	08-2002	Baba et al.	257/778
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 11288975 A	10-1999	Japan	TOMIOKA et al.	H01L 21/60
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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